

<b>Notice of References Cited</b>	Application/Control No. 10/584,790		Applicant(s)/Patent Under Reexamination MIYAKE ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0266378	12-2004	Fukamachi et al.	455/188.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

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